

## EAST SEARCH

12/15/05

L#	Hits	Search String	Databases
S1	2	6,581,191.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S2	2	6,618,839.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S3	473212	((integrated or digital) adj circuit\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S4	1329	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S5	14	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1)) w	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S6	48	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1)) s	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S7	7	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1)) s	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S8	97	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S9	7	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S10	28	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S11	28	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S12	16	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S13	8	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S14	9	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S15	9	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S16	6	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S17	45	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S18	2	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S19	7	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S20	11	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S21	0	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S22	2	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S23	2	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S24	90	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S25	55	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S26	113	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S27	14	circuit\$1) and ((HDL near2 (description or describe\$1)) same debug\$4)) and (state\$	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S28	0	5,937,190.pn. and (control near2 signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S29	6	and ((HDL near2 (description or describe\$1)) same debug\$4)) and (signal with (HD	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S30	17	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S31	2	5,859,993.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S32	2	6,625,787.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S33	2	6,353,906.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S34	2	6,006,022.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S35	2	6,618,854.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S36	2	6,272,451.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S37	2	5,937,190.pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S38	1329	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S39	28	((integrated or digital) adj circuit\$1) and ((HDL near2 (description or describe\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S40	630455	S40 and ((instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S41	486	S40 and ((instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S42	54	S40 and ((instrumentation near2 circuit\$2) with (debug\$3 or test\$3 or simulat\$3 or	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S43	58469	S40 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fat	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S44	73	S41 and S43	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S45	102	S42 or S44	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S46	9	S45 and ("HDL description")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

S47	25	S41 and ((instrumentation near2 circuit\$2) with config\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S48	124	S45 or S46 or S47	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S49	58	S40 and (embedded near2 test near2 circuitry)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S50	384	S40 and ((test near2 circuitry) with config\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S51	8	S49 and S50	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S52	0	S40 and ((embedded near2 test near2 circuitry) same "HDL description")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L1	733888	((integrated or digital) adj circuit\$1) or (electronic near2 system)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L2	557	L1 and (instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L3	75	L1 and ((instrumentation near2 circuit\$2) with (debug\$3 or test\$3 or simulat\$3 or ei	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L4	69199	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fabr	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L5	103	L2 and L4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L6	137	L3 or L5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L7	16	L6 and ("HDL description")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L8	28	L2 and ((instrumentation near2 circuit\$2) with config\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L9	161	L6 or L7 or L8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L10	24	9 and (instrumentation.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L12	11	10 and ("HDL description".CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L13	3	11 and 12	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L11	5	10 and (configuration.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L14	24	10 or 11 or 12 or 13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

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### Results of search set S48:

Document Kind Codes Title	Issue Date	Current OR	Abstract
US 20040178938 A1	20040916	341/143	
US 20040154155 A1	20040812	29/428	
US 20040140529 A1	20040722	257/537	
US 20040093716 A1	20040520	29/593	
US 20040093167 A1	20040513	702/23	
US 20040078101 A1	20040422	700/79	
US 20040027813 A1	20040212	361/767	
US 20040025122 A1	20040205	716/4	
US 20030192183 A1	20040205	361/763	
US 20030182642 A1	20031016	29/857	
US 20030168342 A1	20030925	716/4	
US 20030155940 A1	20030911	205/122	
US 20030134441 A1	20030821	324/762	
US 20030132767 A1	20030717	438/18	
US 20030131325 A1	20030717	324/754	
US 20030090278 A1	20030710	716/4	
US 20030069724 A1	20030515	324/754	
US 20030036776 A1	20030410	703/16	
US 20020198674 A1	20030220	607/9	
US 20020195700 A1	20021226	702/117	
US 20020191368 A1	20021226	257/700	
US 20020135388 A1	20021219	361/306.1	
	20020926	324/754	

US 20020134685 A1	SELF-ALIGNED COAXIAL VIA CAPACITORS	20020926 205/125
US 20020134581 A1	Hybrid capacitor, circuit, and system	20020926 174/260
US 20020132533 A1	Discrete device socket and method of fabrication therefor	20020919 439/862
US 20020113651 A1	Instrumentation amplifier	20020822 330/258
US 20020085334 A1	Multiple tier array capacitor and methods of fabrication therefor	20020704 361/301.4
US 20020075630 A1	Capacitor with extended surface lands and method of fabrication therefor	20020620 361/308.1
US 20020068858 A1	Glucose monitoring instrument having network connectivity	20020606 600/316
US 20010030549 A1	Membrane probing system	20011018 324/758
US 20010010468 A1	Membrane probing system	20010802 324/715
US 20010009785 A1	Method of fabricating a supply decoupling capacitor	20010726 438/210
US 20010009061 A1	Membrane probing system	20010726 29/593
US 6797528 B2	Micro probing tip made by micro machine method	20040928 438/14
US 6757632 B2	Method and apparatus for testing integrated circuits using a synchronization signal	20040629 702/117
US 6730984 B1	Increasing an electrical resistance of a resistor by oxidation or nitridization	20040504 257/537
US 6713860 B2	Electronic assembly and system with vertically connected capacitors	20040330 257/700
US 6708386 B2	Method for probing an electrical device having a layer of oxide thereon	20040323 29/593
US 6672912 B2	Discrete device socket and method of fabrication therefor	20040106 439/862
US 6651325 B2	Method for forming cantilever beam probe card and probe card formed	20031125 29/846
US 6645142 B2	Glucose monitoring instrument having network connectivity	20031111 600/300
US 6636416 B2	Electronic assembly with laterally connected capacitors and manufacturing method	20031021 361/306.1
US 6625557 B1	Mixed signal device under test board interface	20030923 702/117
US 6618839 B1	Method and system for providing an electronic system design with enhanced debug	20030909 716/4
US 6590294 B1	Device for bump probing and method of fabrication	20030708 257/781
US 6581191 B1	Hardware debugging in a hardware description language	20030617 716/4
US 6578264 B1	Method for constructing a membrane probe using a depression	20030617 29/874
US 6565730 B2	Self-aligned coaxial via capacitors	20030520 205/122
US 6538503 B2	Instrumentation amplifier and method for obtaining high common mode rejection	20030325 330/9
US 6532143 B2	Multiple tier array capacitor	20030311 361/301.4
US 6483692 B2	Capacitor with extended surface lands and method of fabrication therefor	20021119 361/308.1
US 6452776 B1	Capacitor with defect isolation and bypass	20020917 361/303
US 6446317 B1	Hybrid capacitor and method of fabrication therefor	20020910 29/25.42
US 6437584 B1	Membrane probing system with local contact scrub	20020820 324/754
US 6407929 B1	Electronic package having embedded capacitors and method of fabrication therefor	20020618 361/763
US 6307387 B1	Membrane probing system with local contact scrub	20011023 324/754
US 6256882 B1	Membrane probing system	20010710 29/874
US 6204715 B1	Signal amplifying circuit	20010320 327/309
US 6195629 B1	Method and system for selectively disabling simulation model instrumentation	20010227 703/17
US 6163724 A	Microprocessor capture detection circuit and method	20001219 607/28
US 6144881 A	Capture detection circuit for pulses and physiologic signals	20001107 607/28
US 6134473 A	Microprocessor capture detection circuit and method	20001017 607/28
US 6122053 A	Apparatus for measuring particle fallout on a surface using a telltale plate	20000919 356/338
US 6075234 A	Non-contact method and apparatus to obtain a timing signal from internal integrator	20000613 250/207
US 6042249 A	Illuminator optical assembly for an analytical instrument and methods of alignment	20000328 362/259
US 6027980 A	Method of forming a decoupling capacitor	20000222 438/396
US 5991324 A	Reliable, modular, production quality narrow-band KRF excimer laser	19991123 372/57
US 5973910 A	Decoupling capacitor in an integrated circuit	19991026 361/313
US 5973842 A	Method and apparatus for an optical illuminator assembly and its alignment	19991026 359/619
US 5954756 A	Microprocessor capture detection circuit and method	19990921 607/28
US 5953661 A	Autonomous node for a test instrument system having a distributed logic nodal arc	19990914 702/31
US 5936986 A	Methods and apparatus for driving a laser diode	19990810 372/38.02
US 5934885 A	Reagent pump assembly	19990810 417/392
US 5914613 A	Membrane probing system with local contact scrub	19990622 324/754

US 5908599 A	Heated reaction chamber in a unified fluid circuit of a hematology diagnostic instrument	19990601 422/50
US 5883378 A	Apparatus and methods for transmitting electrical signals indicative of optical interference	19990316 250/214A
US 5873898 A	Microprocessor capture detection circuit and method	19990223 607/28
US 5872627 A	Method and apparatus for detecting scattered light in an analytical instrument	19990216 356/338
US 5871512 A	Microprocessor capture detection circuit and method	19990216 607/28
US 5844685 A	Reference laser beam sampling apparatus	19981201 356/433
US 5793218 A	Generic interface test adapter	19980811 324/754
US 5788927 A	Unified fluid circuit assembly for a clinical hematology instrument	19980804 422/63
US 5772963 A	Analytical instrument having a control area network and distributed logic nodes	19980630 422/67
US 5745308 A	Methods and apparatus for an optical illuminator assembly and its alignment	19980428 359/818
US 5719667 A	Apparatus for filtering a laser beam in an analytical instrument	19980217 356/73
US 5701082 A	Probe for sensing modulated signals and method of using same	19971223 324/628
US 5691486 A	Apparatus and methods for selecting a variable number of test sample aliquots to n	19971125 73/863.73
US 5689192 A	Method for simulating a controlled voltage for testing circuits for electromagnetic susceptibility	19971118 324/627
US 5648926 A	Silicon neuron	19970715 708/801
US 5585765 A	Low power RC oscillator using a low voltage bias circuit	19961217 331/111
US 5583739 A	Capacitor fabricated on a substrate containing electronic circuitry	19961210 361/313
US 5570067 A	Microprocessor RC oscillator having hysteresis produced by switching current sources	19961029 331/111
US 5552715 A	Apparatus for low cost electromagnetic field susceptibility testing	19960903 324/627
US 5472900 A	Capacitor fabricated on a substrate containing electronic circuitry	19951205 438/396
US 5449903 A	Methods of fabricating integrated, aligned tunneling tip pairs	19950912 250/306
US 5416429 A	Probe assembly for testing integrated circuits	19950516 324/762
US 5414345 A	Apparatus and method for low cost electromagnetic field susceptibility testing	19950509 324/72.5
US 5311486 A	Timing generation in an automatic electrical test system	19940510 368/10
US 5235187 A	Methods of fabricating integrated, aligned tunneling tip pairs	19930810 250/306
US 5103378 A	Hinged interlocking receiver for mainframe card cage	19920407 361/802
US 4907230 A	Apparatus and method for testing printed circuit boards and their components	19900306 714/724
US 4856530 A	Catheter identifier and method	19890815 600/505
US 4785175 A	Inspection of buried pipelines	19881115 250/360.1
US 4675594 A	Voltage-to-current converter	19870623 323/317
US 4579600 A	Method of making zero temperature coefficient of resistance resistors	19860401 438/385
US 4400789 A	Magnetic heading simulator	19830823 703/13
US 4395677 A	Hall Effect tester for heated window grids	19830726 324/117H
US 4305319 A	Modular drum generator	19811215 84/611
US 4282515 A	Analog to digital encoding system with an encoder structure incorporating instrument	19810804 341/118
US 4262248 A	System for servicing process instrumentation	19810414 324/72.5
US 4232271 A	Instrumentation amplifier with extended common mode range	19801104 330/258
US 4135423 A	Automatic rhythm generator	19790123 84/635
US 3818751 A	TESTING APPARATUS FOR ELASTOMERS	19740625 374/46
US 3654585 A	COORDINATE CONVERSION FOR THE TESTING OF PRINTED CIRCUIT BOARDS	19720404 439/65
US 3636450 A	DIGITAL MOS FET CHARACTERISTIC TESTER	19720118 324/769
US 3629695 A	PRERECORDED ELECTRONIC TAPE CONTROLLED CIRCUIT TESTING SYSTEM	19711221 324/73.1
JP 2003287587 A	PLANT PROTECTION INSTRUMENTATION DEVICE	20031010
US 6618839 B	Fabricated integrated circuit debugging method e.g. for application specific integrated	20030909 55
US 20030131325 A	Fabricated integrated circuits debugging method for electronic system designs, invention	20030710 96
US 20030069724 A	Computer system debugging method involves translating debug data received from	20030410 96
US 6075234 A	Integrated circuit test instrumentation triggering method involves applying trigger signal	20000613
EP 570101 A	Mixed analogue and digital integrated circuit for physiological instrumentation - has	19950419
DD 246433 A	Interference pulse detection circuit for instrumentation testing - has input or-gate for	19870603

Interference checking done

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L#	Hits	Search String	Databases
L1	733888	((integrated or digital) adj circuit\$1) or (electronic near2 system)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L2	557	L1 and (instrumentation near2 circuit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L3	75	L1 and (((instrumentation near2 circuit\$2) with (debug\$3 or test\$3 or simulat\$3 or e	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L4	69199	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fabr	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L5	103	L2 and L4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L6	137	L3 or L5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L7	16	L6 and ("HDL description")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L8	28	L2 and (((instrumentation near2 circuit\$2) with configur\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L9	161	L6 or L7 or L8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L10	24	9 and (instrumentation.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L12	11	10 and ("HDL description".CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L13	3	11 and 12	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L11	5	10 and (configuration.CLM.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L14	24	10 or 11 or 12 or 13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
L15	17594	L1 and (((integrated or digital) adj circuit\$1) or (electronic near2 system)) with fabr	US-PGPUB
L16	144	L1 and (instrumentation near2 circuit\$2)	US-PGPUB
L17	43	15 and 16	US-PGPUB
L18	8	17 and (instrumentation.CLM.)	US-PGPUB
L19	6	17 and ("HDL description".CLM.)	US-PGPUB
L21	1	17 and (configuration.CLM.)	US-PGPUB
L22	8	18 or 19 or 21	US-PGPUB

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### Results of search set S48:

Document Kind	Codes	Title	Issue Date	Current OR	Abstract
US	20040178938 A1	Circuit for direct digital delta-sigma conversion of variable electrical capacitance	20040916	341/143	
US	20040154155 A1	Membrane probing system	20040812	29/428	
US	20040140529 A1	Increasing an electrical resistance of a resistor by oxidation or nitridization	20040722	257/537	
US	20040093716 A1	Membrane probing system	20040520	29/593	
US	20040093167 A1	Analyte detection system with software download capabilities	20040513	702/23	
US	20040078101 A1	Plant protective instrumentation equipment	20040422	700/79	
US	20040027813 A1	Manufacturing methods for an electronic assembly with vertically connected capac	20040212	361/767	
US	20040025122 A1	Hardware-based HDL code coverage and design analysis	20040205	716/4	
US	20040022038 A1	Electronic package with back side, cavity mounted capacitors and method of fabric	20040205	361/763	
US	20030192183 A1	Method for constructing a membrane probe using a depression	20031016	29/857	
US	20030182642 A1	Hardware debugging in a hardware description language	20030925	716/4	
US	20030168342 A1	Self-aligned coaxial via capacitors	20030911	205/122	
US	20030155940 A1	Method for forming cantilever beam probe card and probe card formed	20030821	324/762	

US 20030134441 A1	Micro probing tip made by micro machine method	20030717 438/18
US 20030132767 A1	Membrane probing system	20030717 324/754
US 20030131325 A1	Method and user interface for debugging an electronic system	20030710 716/A
US 20030090278 A1	Membrane probing system	20030515 324/754
US 20030069724 A1	Method and system for debugging an electronic system using instrumentation circuit	20030410 703/16
US 20030036776 A1	MRI-compatible implantable device	20030220 607/9
US 20020198674 A1	Method for testing integrated circuits	20021226 702/117
US 20020195700 A1	Electronic assembly with vertically connected capacitors and manufacturing method	20021226 257/700
US 20020191368 A1	Electronic assembly with laterally connected capacitors and manufacturing method	20021219 361/306.1
US 20020135388 A1	Membrane probing system with local contact scrub	20020926 324/754
US 20020134685 A1	SELF-ALIGNED COAXIAL VIA CAPACITORS	20020926 205/125
US 20020134581 A1	Hybrid capacitor, circuit, and system	20020926 174/260
US 20020132533 A1	Discrete device socket and method of fabrication therefor	20020919 439/862
US 20020113651 A1	Instrumentation amplifier	20020822 330/258
US 20020085334 A1	Multiple tier array capacitor and methods of fabrication therefor	20020704 361/301.4
US 20020075630 A1	Capacitor with extended surface lands and method of fabrication therefor	20020620 361/308.1
US 20020068858 A1	Glucose monitoring instrument having network connectivity	20020606 600/316
US 20010030549 A1	Membrane probing system	20011018 324/758
US 20010010468 A1	Membrane probing system	20010802 324/715
US 20010009785 A1	Method of fabricating a supply decoupling capacitor	20010726 438/210
US 20010009061 A1	Membrane probing system	20010726 29/593
US 6797528 B2	Micro probing tip made by micro machine method	20040928 438/14
US 6757632 B2	Method and apparatus for testing integrated circuits using a synchronization signal	20040629 702/117
US 6730984 B1	Increasing an electrical resistance of a resistor by oxidation or nitridization	20040504 257/537
US 6713860 B2	Electronic assembly and system with vertically connected capacitors	20040330 257/700
US 6708386 B2	Method for probing an electrical device having a layer of oxide thereon	20040323 29/593
US 6672912 B2	Discrete device socket and method of fabrication therefor	20040106 439/862
US 6651325 B2	Method for forming cantilever beam probe card and probe card formed	20031125 29/846
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US 6636416 B2	Electronic assembly with laterally connected capacitors and manufacturing method	20031021 361/306.1
US 6625557 B1	Mixed signal device under test board interface	20030923 702/117
US 6618839 B1	Method and system for providing an electronic system design with enhanced debugging	20030909 716/4
US 6590294 B1	Device for bump probing and method of fabrication	20030708 257/781
US 6581191 B1	Hardware debugging in a hardware description language	20030617 716/4
US 6578264 B1	Method for constructing a membrane probe using a depression	20030617 29/874
US 6565730 B2	Self-aligned coaxial via capacitors	20030520 205/122
US 6538503 B2	Instrumentation amplifier and method for obtaining high common mode rejection	20030325 330/9
US 6532143 B2	Multiple tier array capacitor	20030311 361/301.4
US 6483692 B2	Capacitor with extended surface lands and method of fabrication therefor	20021119 361/308.1
US 6452776 B1	Capacitor with defect isolation and bypass	20020917 361/303
US 6446317 B1	Hybrid capacitor and method of fabrication therefor	20020910 29/25.42
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US 6163724 A	Microprocessor capture detection circuit and method	20001219 607/28
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